

Patent Claims

1. A method for current measurement at a potential
5 which is at a higher value than zero potential, the
current value being measured in the form of an analog
signal and its information being transmitted, after A/D
conversion, in the form of a digital signal to an
evaluation unit which is at ground potential,
10 characterized in that the analog signal is subjected to
compression before A/D conversion and transmission, and
in that the digital signal is subjected to expansion
after transmission at ground potential.
- 15 2. The method as claimed in claim 1, characterized in
that compression and expansion are effected
logarithmically.
3. The method as claimed in claim 1, characterized in
20 that compression and expansion are effected on the
basis of the stipulation of root functions.
4. The method as claimed in one of the preceding
claims, characterized in that temperature compensation
25 is effected.
5. The method as claimed in claim 4, characterized in
that the measuring device and shunt are thermally
coupled for the purpose of temperature compensation.
- 30 6. The method as claimed in one of the preceding
claims, in which, in order to evaluate a measurement
signal which, at a higher potential than zero
potential, is in the form of an analog value in a
35 measuring device that requires a supply current, having
the following measures:
- the compressed information content of the
measurement signal is transmitted, after A/D

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conversion, in the form of a digital signal to the evaluation unit, which is at ground potential,

5 -. after A/D conversion of the measurement signal,
 the digital signal produced provides the clock for
 modulating the supply current, with the result
 that the modulated supply current for the
 measuring device likewise performs the function of
 the carrier for the information content of the
 measurement signal.

10 7. A circuit arrangement for carrying out the method
 as claimed in claim 1 or one of claims 2 to 6, for use
 when measuring the current at a shunt, in which the
 voltage drop is evaluated as a measure of the current
 after amplification, said circuit arrangement having a
 shunt (1; 61, 61', 61''; 71), an amplifier (2) for the
15 voltage signal that is tapped off at the shunt (1; 61,
 61', 61''; 71), an analog/digital converter (3) and an
 evaluation unit (5, 65, 7) and also having means for
 supplying the measuring components (2, 3) with current,
 characterized in that further means (4, 6) for signal
20 compression and signal expansion are provided.

 8. The circuit arrangement as claimed in claim 7,
 characterized in that means for temperature
 compensation are additionally provided.

25 9. The circuit arrangement as claimed in claim 7,
 characterized in that a unit for signal compression is
 connected upstream of the A/D converter (3).

30 10. The circuit arrangement as claimed in claim 7,
 characterized in that the means for signal expansion
 are integrated in the evaluation unit (5, 65, 75),
 preferably in the existing microcontroller in the form
 of software.

35 11. The circuit arrangement as claimed in claim 8,
 characterized in that means for temperature
 compensation have a temperature-dependent reference
 voltage source (6).

12. The circuit arrangement as claimed in one of
claims 7 to 11, characterized in that means (85, 95)
for short-circuit disconnection and/or overload
5 disconnection are provided.

13. The circuit arrangement as claimed in claim 12,
characterized in that a first comparator (85), which
compares the instantaneous value of the current with a
10 first threshold value and produces a signal for short-
circuit disconnection when said first threshold value
is exceeded, is provided.

14. The circuit arrangement as claimed in claim 12,
15 characterized in that a second comparator (95), which
compares the instantaneous temperature of the load with
a second threshold value and outputs a signal for
overload disconnection when said second threshold value
is exceeded, is provided.

20 15. The circuit arrangement as claimed in claim 14,
characterized in that a thermal model (94) of the load
is provided, said model being used to ascertain the
instantaneous temperature of the load (80) from the
25 current measured.